

<b>Notice of References Cited</b>	Application/Control No. 10/058,722	Applicant(s)/Patent Under Reexamination LU ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0141971 A1	07-2003	Heiken, Edward Daniel JR.	340/506
*	B	US-6,999,414 B2	02-2006	Gummalla et al.	370/230
*	C	US-2002/0066110 A1	05-2002	Cloonan et al.	725/111
*	D	US-2002/0144284 A1	10-2002	Burroughs et al.	725/111
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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